



POZVÁNKA
na 266. seminář ÚTEF ČVUT v Praze
pod záštitou Československé sekce NPSS IEEE

Ultra-Fast Silicon Detectors

Prof. Hartmut F.-W. Sadrozinski

Santa Cruz Institute for Particle Physics SCIPP
University of California Santa Cruz, CA, USA

Abstract: We are developing Ultra-Fast Silicon Detectors UFSD, providing experiments with high-precision 4D capability. The principle is based on fast collection time, i.e. thin sensors, and requires sensors with internal gain. I will discuss applications in a wide range of fields, and expected performance based on estimation of the signal-to-noise ratio. I will report on electrical tests and TCT charge collection data with so-called low-gain avalanche detectors (LGAD). I will compare the bias dependence of the pulse shapes of traditional sensors and of LGAD sensors with different dopant density of the diffusion layer, and extract the internal gain.

Seminář se bude konat v úterý 12. listopadu 2013 ve 14 hodin
v zasedací místnosti ÚTEF ČVUT, Praha 2 - Albertov, Horská 3a/22

Ing. František Krejčí
tajemník semináře

Ing. Stanislav Pospíšil, DrSc.
ředitel

Doc. Ing. Carlos Granja, Ph.D.
předseda NPSS, ČS IEEE

NUCLEAR & PLASMA SCIENCES SOCIETY CHAPTER

IEEE Czechoslovakia Section
<http://www.ieee.cz/en/nps>

 **IEEE**
Czechoslovakia Section